PINTAIL TECHNOLOGIES

PRESS RELEASE

Pintail Announces Expanded Adaptive Test Solutions

Five Next Generation Products Added to SwifTest™ Family

Dallas, TX (April 24, 2008) – Pintail Technologies, a leading supplier of Adaptive Test software for semiconductor manufacturing, today announced the release of a new generation of products for its popular SwifTest platform. With the SwifTest platform having over four years of production experience, the newest SwifTest products offer users the ability to dynamically optimize test time and test coverage, improve device quality and reliability, and actively monitor and improve device yield during production testing at both wafer probe and final (packaged) test.

"Over 500 copies of SwifTest are in production worldwide today and over 1 billion devices have been shipped by our customers using the SwifTest adaptive test platform," stated Taylor Scanlon, president and chief executive officer of Pintail. "The introduction of these new products further extends our lead in adaptive test."

A major enhancement included in all of the new SwifTest products is the ability for users to add their own algorithms via a simple Java based interface. The new products also run 4-5 times faster and require 25% less memory than earlier SwifTest products.

SwifTest-AMX™ (Advanced Monitoring Executive) captures data in real-time from automated test equipment (ATE) and makes it available to upstream data base systems or to the adaptive test modules described below. In addition to traditional STDF, SwifTest-AMX can now be easily programmed to accept any format of test data.

SwifTest-FOX™ (Fast Outlier Extraction) includes advanced dynamic outlier detection algorithms for improving device reliability at both probe and final test. Users can also reduce their burn-in costs using this software. Many of the algorithms are provided under license from Avago Technologies (See March 12, 2008). Outlier detection may be used within a single device under test (DUT) or across an entire wafer or lot.

SwifTest-TTO™ (Test Time Optimization) performs real-time, statistical test flow optimization to reduce cost of test. It adaptively increases or decreases test coverage based upon the monitored quality and yield of the device. TTO can be used for both parametric tests and functional patterns and may be used at both probe and final test.

SwifTest-DTI™ (Dynamic Test Interface) is used to support a variety of miscellaneous adaptive test algorithms. Examples include Pintail's new Dynamic Site-site Calibration (DSC) which can automatically correct certain forms of site-site variation on-the-fly and thus recover yield losses at test.

SwifTest-MAX™ (Monitoring Actions) provides programmable, real-time triggers and trigger actions that can support sophisticated monitoring strategies based upon multiple bin counters, cumulative bin counters, windowed probabilities, wafer zones, etc. Users will experience improved efficiencies and yield during test operations.

SwifTest is available on most leading ATEs and is supported in production by nearly all the test subcontractors in the semiconductor industry.

About Pintail Technologies

Pintail Technologies is a semiconductor test improvement and yield learning company that provides breakthrough software to reduce the cost of test and increase production output and quality through existing test equipment and programs. Pintail has created the first test improvement solutions to combine real-time, on-line, adaptive test with powerful web-based database applications. Fabless and integrated device manufacturers (IDM) worldwide, in collaboration with leading assembly and test suppliers use Pintail tools to increase competitive advantage and improve responsiveness to test issues. Pintail has sales offices in Dallas, Austin, San Jose, Seoul, Singapore, and Taiwan. See www.pintail.com.

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